## Prelocalization in semimetals

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The Fermi energy close to a band edge provides a conventional localization only when a onedimensional residual resistance is large compared to  $\pi \hbar/e^2$ . Prior to the localization, the resistance increases first quadratically and then oscillates (between large and small values) with the length ("prelocalization"). There are several temperature regions, where the resistance may increase and decrease with temperature.

Recently it was noticed<sup>1</sup> that  $\delta$ -function substitutional impurities at the band edge of the pure system do not give rise to the localization even in one dimension (1D). Instead, then<sup>1</sup> 1D residual resistance  $R_r \propto L^2$ , L being the length. In semimetals the Fermi energy is close to the band edge, and a direct calculation<sup>2,3</sup> of the localization length  $L_0$  in a wire leads to  $L_0 \sim 8k |v_a \cot k - k| S/c_1 c_2 v'^2$  when  $|v_a|$  $<< k | \tan k |$ . Here  $v_a = v_1 c_2 + v_2 c_2; v' = v_1 - v_2; v_1$ and  $v_2$  are the dimensionless potentials of an impurity and a basic atom;  $c_1$  and  $c_2$  are their concentrations  $(c_1 + c_2 = 1)$ ; k is the Fermi wave vector; S is the wire cross-section area; the interlattice spacing is 1. In semimetals (where  $k \approx \pi, 2\pi, \ldots$ )  $|\cot k| >> 1$ . Thus,  $L_0 \propto |\cot k| S$  remains large compared to the Thouless<sup>4</sup> inelastic diffusion length  $L_D$ down to very low temperatures. This may explain the absence of the localization in the experiments<sup>5</sup> on Bi.

Usually, according to the scaling theory,<sup>6</sup> at zero temperature the localization follows Ohm's law  $(R_r \propto L)$  at the dimensionless  $R_r \sim 1$ . In this paper I prove that in semimetals  $L \sim L_0$  implies  $R_r >> 1$ . Prior to the localization, the dependence of  $R_r$  on Lis very special. It is characteristic of each random system (which is natural for L less than the correlation length  $\sim L_0$ )—see Fig. 1. The representative<sup>6,7</sup> ensemble average  $\langle R_r \rangle$  is  $\propto L$  only when L is small compared to an elastic mean free path l (if  $l \sim 1$ , this region is extinct). When L > l, but  $L < L_0$ , then first  $\langle R_r \rangle \propto L^2$  (Fig. 2), and later oscillates between large values (Fig. 3). This new region, which is different from both weak and strong localization and which may exist only in semimetals, I denote as the "prelocalization." The temperature dependence of the resistance R(T) in this region is also unusual (see later in this paper). I prove that  $l \sim 4k^2/c_1c_2v'^2$ , so  $L_0 \sim lS |v_a \cot k| >> l$ . Thus, the prelocalization region where  $l < L < L_0$  (and  $\langle R_r \rangle >> 1$ ) is rather large. To elucidate these results, consider a unity interlattice spacing and a wave vector  $k = \pi$  at the band edge. Such k implies the wave-function phase shift  $(n'-n)\pi$  on the way from the *n*th to *n'*th site and

the phase shift  $2(n'-n)\pi$  for a round trip. Since the latter phase shift is unimportant,  $k = \pi$  does not "see" any randomness in the substitutional impurity positions. Thus, it does not give rise to any localization, and we find instead<sup>1</sup>  $R_r \propto L^2$ . When  $k \approx \pi$  and the meaningful phase shift at an average interimpurity distance is small, then a phase-shift randomization occurs only at large distances  $\propto |\pi - k|^{-1}$ . Impurity position randomness is averaged out at such distances, so only impurity concentration fluctuations matter. When the single impurity scattering is weak, then the difference of the "total" phase shift  $(\pi - k)L$  from an integer of  $2\pi$  oscillates with L and this leads to oscillations in  $R_r$  and  $\langle R_r \rangle$ . When the individual scattering is strong, then a particle bounces



FIG. 1. Dependence of the one-dimensional (1D) residual resistance  $R_r$  on the length L. Interlattice spacing is 1, dimensionless wave vector k = 3.14, dimensionless impurity potentials  $v_1 = 10$ ,  $v_2 = 0$ ; impurity concentration  $c_1 = 0.125$ . Note a large scale  $R_r$  change (e.g., from 70 to  $9 \times 10^{-4}$  to 100 at  $L \sim 1500$ ).

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FIG. 2. 1D residual resistance  $\langle R_r \rangle$ , averaged over 300 samples. Impurity concentration  $c_1 = 0.5$ ; k and v are the same as in Fig. 1.

back and forth many times between adjacent impurities, its effective path at L increases significantly, and thus the period of the oscillations of  $\langle R_r \rangle$  and  $R_r$  decreases. If, for instance,  $v_2 = 0$  and  $v_1 > 2k \approx 2\pi$ then an individual potential  $v_1$  implies the transmission coefficient  $t \sim (1 + v_1^2/4k^2)^{-1}$ , thus  $\sim t^{-1}$ "bouncings" and, therefore, the period of oscillations

$$L_1 \sim t/(\pi - k) \sim 4\pi^2/v_1^2(\pi - k)$$



FIG. 3. Same as Fig. 2, but on a larger length L scale. Note large-scale oscillations at L < 1000 and a conventional localization when  $\langle R \rangle > 500$ .

(When  $L \ll L_1$ , then  $\langle R_r \rangle \propto L^2$ .) An elastic mean free path

$$l - 4k^2/v_1^2c_1c_2 = 4\pi^2/v_1^2c_1c_2$$

is small compared to  $L_1$  when  $c_1, c_2 > \pi - k$ , i.e., up to low impurity concentrations. The prelocalization persists until the length L becomes of order of or larger than the localization length  $L_0 \sim 8\pi S/((\pi - k)c_2v_1)$ . (Note that  $L_0 \propto S$ , while  $L_1$  and l are independent of S.) The latter remains large compared to the inelastic diffusion length  $L_D \sim \sqrt{ll_{in}}$  until an inelastic mean-free-path length  $l_{in}$  becomes

$$l_{\rm in}^{(0)} \sim L_D^2/l \sim 16S^2c_1/(\pi-k)^2c_2$$

where S (in the dimensionless units) is the number of sites per cross section. Consider the case of  $c_1=0.2$ ,  $v_1=10$ , and  $\pi - k = 0.01$ . Then  $l \sim 2$ ; a "conventional"  $L_0 \sim lS \sim 2S$ , and  $l_{in}^{(0)} \sim L_D^2/l \sim 2S^2$ , while  $L_1 \sim 40$ , the "true"  $L_0 \sim 250S$  and  $l_{in}^{(0)} \sim L_D^2/l \sim 30000S^2$ . In a whisker  $300 \times 300$ atoms in a cross section  $L_0 \sim L_D$  only at the temperatures low enough to provide  $l_{in}^{(0)} \sim 3 \times 10^9$  interlattice spacings, i.e.,  $l_{in} \sim 1$  m. Since the crucial quantity is  $\pi - k$ ,  $L_D$  can be significantly affected by a small change in the Fermi energy  $\epsilon_F$ , which may be provided by external pressure or magnetic field which leads to a paramagnetic quantization.

A crucial point in all this reasoning is that the impurities are vacancies or  $\delta$ -function substitutions. A general case will be considered elsewhere.

According to Ref. 2, the residual resistance  $R_r$  for a potential  $V = \sum_{n=1}^{L} v_n \delta(x - n)$ , where  $v_n$  is randomly chosen to be  $v_1$  (with the probability  $c_1$ ) or  $v_2$ (with the probability  $c_2$ ), equals

$$R_r = [\exp(G_L^{(+)}) + \exp(G_L^{(-)}) - 2]/4 , \qquad (1)$$

$$G_L^{(\pm)} = \sum_{n=1}^{L} \ln \left[ \frac{(1 + X_n^{(\pm)^2})}{(\omega_{n-1} + \omega_{n-1}^{-1} X_n^{(\pm)^2})} \right] , \qquad (2)$$

where

$$\begin{aligned} X_{n+1} &= \omega_n (X_n - r_n) / (1 + r_n X_n) , \\ \omega_n &= \tan^2 (h_n / 2 + \pi / 2) , \\ r_n &= \tan[k - (h_n + h_{n-1}) / 2] , \\ h_n &= \arctan(\nu_n / 2k), h_0 = 0; X_1^{(\pm)} = \pm 1 . \end{aligned}$$

Equations (1) and (2) lead to the plots in Figs. 1–5. The approach is readily applicable to any sequence of arbitrary and arbitrarily located nonoverlapping potentials. In Figs. 1–5 holes localized by impurity potential barriers were considered. According to the above recurrence relations, electron (with  $k > \pi$ ) scattering at impurity potential wells is similar. The energy of electrons between potential barriers and holes between potential wells lies either in the gap or



FIG. 4. Residual resistance  $R_{av}$ , averaged over 9000 samples and the length; c, k, v are the same as in Fig. 2.

close to an energy gap of the average potential. In this case their localization differs less from the conventional picture. The scattering of small k's is the strongest because an electron with a small velocity proportional to k spends a large time proportional to 1/k near an impurity. Its localization differs from a conventional one only in the case of a weak well scattering.

In semimetals, conductivities of electrons and holes add up, so the larger conductivity dominates. When electrons are in the first band  $(k \approx 0)$ , the dominant hole conductivity is very different for impurity potential barriers and wells.



FIG. 5. Residual resistance  $R_{av}$ , averaged over 300 samples and the length, for impurity concentrations  $c_1 = 0.125$ , 0.25, 0.5; k and v are the same as in Fig. 1. Note that at L > 9000 resistance *decreases* when impurity concentration *increases*, in agreement with Ref. 2.

A large magnetic field, which essentially alters the distance between the Fermi energy and a band edge and thus  $L_0$ , may change the resistance by orders of magnitude in the strong localization case.

We introduce  $X_n \equiv \tan[\pm \pi/4 - (n-1)k + b_n^{\pm}]$ , where  $b_1^{\pm} = 0$ , and derive the recurrence for  $b_n^{\pm}$ . When  $h_n \ll 1$ , we determine  $b_n^{\pm}$  in a linear approximation in  $h_n$  and evaluate  $R_r$  by Eqs. (1) and (2). After simple algebraic transformations one obtains

$$R_{r} \approx \left(\sum_{n=1}^{L} h_{n} \cos(2nk)\right)^{2} + \left(\sum_{n=1}^{L} h_{n} \sin(2nk)\right)^{2}.$$
 (3)

Then by Eq. (3),

$$\langle R_r \rangle \approx L \Delta h^2 + \langle h \rangle^2 \sin^2(kL) / \sin^2 k$$
, (4)

where  $\Delta h^2 = \langle h^2 \rangle - \langle h \rangle^2$ , and where triangular brackets denote ensemble average.

In the general case in the prelocalization region  $\langle R_r \rangle$  can be evaluated following the approach of Refs. 2 and 8. In the localization region a representative  $R_r$  and  $L_0$  were evaluated in Ref. 2.

In Ref. 3 the calculation of the resistance of a wire was mapped on that of a 1D random potential. The latter equals the wire impurity potential averaged over all possible cross-section impurity positions. The resulting equation, replacing Eq. (4), reads

$$\langle R_r \rangle \sim L/Sl + v_{\rm av}^2 \sin^2(kL)/4k^2 \sin^2k \quad . \tag{5}$$

The first term is the classical Ohmic term with the elastic mean free path  $l \sim 4k^2/c_1c_2v'^2$ .

At finite temperature T, when the inelastic diffusion length  $L_D$  (i.e., the direct distance between two consecutive inelastic collisions,  $L_D \propto \tau_{in}^{1/2}$ ,  $\tau_{in}$  being an inelastic mean-free-path time) is small compared to  $L_0$ , then one should average over all lengths L of the order of  $L_D$ , and the conductivity proportional to L is obtained in the leading approximation for  $L >> L_D$ .

Therefore a resistance R(T) is related to

$$R_{\rm av}(L) \equiv L^{-1} \sum_{L'=1}^{L} \langle R_r(L') \rangle$$

by the equation  $R(T) \sim R_{av}(L_D)(L/L_D)$ .

According to Eq. (4), when  $L < 1/|\pi - k|$ , then  $R_{av} \propto L^2$ , while  $L >> 1/|\pi - k|$  leads to

$$R_{\rm av}(L) \sim L/2Sl + v_{\rm av}^2/8k^2\sin^2 k \equiv A + BL$$
 . (6)

Weak oscillations, provided by Eq. (4), are neglected in Eq. (5). The numerical calculation of  $R_{av}(L)$ , according to Eqs. (1) and (2), is presented in Fig. 4 and, for different impurity concentrations, in Fig. 5.

When the temperature T decreases,  $R(T) \propto \tau_{in}^{-1}$ and decreases with T (the "classical" temperature dependence), if  $L_D < l$ . Then, when l < L < 1/ $|\pi - k|$  and  $R_{av}(L) \propto L^2$ , a prelocalization regime starts:  $R(T) \propto \tau_{in}^{1/2}$  and increases with T. Then, when  $R_{av}(L) \simeq A + BL$ ;  $R(T) \simeq \tau_{in}^{-1/2}$  and decreases with T. This decrease continues as long as  $R_{av}/L$  decreases, i.e., until a straight line from L = 0 to a given L becomes tangent to  $R_{av}(L)$ . Weak R(T)oscillations with T, related to  $R_{av}$  oscillations with L, may also be possible in the prelocalization region. Finally, R(T) gives rise to the Thouless regime<sup>4</sup>:  $R(T) \propto \tau_{\text{in}}^{-1}$  when  $L_D > L_0$  and  $\ln R(T) \propto T^{-1}$  at very low temperatures. Usually even at high temperatures  $L_D >> 1/|\pi - k|, l$ ; this may extinguish the first two regions  $[R(T) \propto \tau_{in}^{-1} \text{ and } R(T) \propto \tau_{in}^{1/2}]$ , unless a certain pressure, and/or magnetic field, and/or impurity concentration provide  $|\pi - k| < 1/L_D$  and/or  $L_D < l$ . Since the prelocalization region persists up to very large values of  $R_{av}$ , the R(T) decrease with T persists up to extremely low temperatures. This was actually observed in experiments<sup>5</sup> on Bi.

In this calculation T has everywhere been assumed to be small compared to the Fermi energy  $\epsilon_F$  and thus it does not affect available values of  $|\pi - k|$ . The increase in  $T \ge \epsilon_F$  would decrease the available

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values of  $|\pi - k|$  and thus decrease the corresponding resistance.

Since  $L_0$  is very different for electrons and holes in semimetals,<sup>2</sup> at low temperatures electrons may be localized while holes are not, or the other way around. This may be verified in a strong magnetic field H, because then the effective electron and hole densities are no longer compensated, and  $R \propto H^2$  should be replaced by the R(H) dependence, which exhibits saturation.

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